Generalized Mueller matrix Ellipsometry of 3-D spherical photonic bandgap structures

Laser Assisted Nano-Engineering Lab

UNIVERSITY OF NEBRASKA-LINCOLN

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Our messages

- Angle-resolved Generalized Mueller matrix Ellipsometry can inform about structural order and optical properties of nano-scale periodic photonic bandgap (PBG) structures.
- The angle-resolved images reveal strong polarization mode coupling within the photonic bandgap and provide depth resolved structural properties.

